

## CLAIMS

1. A method for determining a feature location, comprising:  
providing left and right camera images of the feature;  
locating the feature in the left camera image and in the right camera image  
using bunch graph matching;  
determining the feature location in multiple dimensions including depth based  
on the feature locations in the left camera image and the right camera image.
2. A method for determining a feature location, comprising:  
providing left and right camera images of the feature;  
locating the feature in the left camera image and in the right camera image  
using image analysis based on wavelet component values generated from wavelet  
transformations of the camera images;  
determining the feature location in multiple dimensions including depth based  
on the feature locations in the left camera image and the right camera image.
3. A method for determining a feature location as defined in claim 2,  
wherein the wavelet transformations use Gabor wavelets.
4. Apparatus for determining a feature location, comprising:  
means for providing left and right camera images of the feature;  
means for locating the feature in the left camera image and in the right camera  
image using image analysis based on wavelet component values generated from  
wavelet transformations of the camera images;  
means for determining the feature location in multiple dimensions including  
depth based on the feature locations in the left camera image and the right camera  
image.

5. A method for determining a feature location as defined in claim 4, wherein the wavelet transformations use Gabor wavelets.

6. A method for determining a feature location, comprising:  
providing first and second spaced-apart camera images of the feature;  
locating the feature in the first camera image using image analysis based on wavelet component values generated from wavelet transformations of the first camera image and locating the feature in the second camera image; and  
determining the feature location in multiple dimensions including depth based on the feature location in the first camera image and the feature location in the second camera image.

7. A method for determining a feature location as defined in claim 6, wherein the wavelet transformations use Gabor wavelets.

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